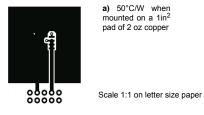


Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
Off Chara	acteristics						
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	40			V	
ΔBV_{DSS} ΔT_J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		34		mV/°C	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 32V, V_{GS} = 0V$ $T_{.1} = 55^{\circ}C$			1 10	μΑ μΑ	
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA	
On Chara	acteristics (Note 2)						
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1	1.8	3	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		-5		mV/°C	
	Drain to Source On Resistance	V _{GS} = 10V, I _D = 12.8A		9	10.5		
r _{DS(on)}		V _{GS} = 4.5V, I _D = 11.4A		10	12.3	mΩ	
		V _{GS} = 10V, I _D = 12.8A,T _J = 125°C		13	15		
9 FS	Forward Transconductance	V _{DS} = 10V, I _D = 12.8A		75.3		S	
C _{iss} C _{oss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 20V, V _{GS} = 0V, f = 1MHz		2000 250 150	2600 350 250	pF pF pF	
C _{rss}	Gate Resistance	f = 1MHz		150 1.3	250	p⊢ Ω	
_{Rg} Switchin	g Characteristics	1 - 11/11/2		1.0		52	
t _{d(on)}	Turn-On Delay Time	$M_{} = 20M_{} = 12.80$		11	20	ns	
t _r	Rise Time	$V_{DD} = 20V, I_D = 12.8A$ $V_{GS} = 10V, R_{GEN} = 4.5\Omega$		14	25	ns	
t _{d(off)}	Turn-Off Delay Time	GS GS GEN GEN		27	42	ns	
t _f	Fall Time			7	14	ns	
Qg	Total Gate Charge at V _{GS} = 10V			35	49	nC	
Qg	Total Gate Charge at V_{GS} = 5V	V _{DS} = 20V, I _D = 12.8A,		19	27	nC	
Q _{gs}	Gate to Source Gate Charge			6		nC	
Q _{gd}	Gate to Drain "Miller"Charge			7		nC	
	urce Diode Characteristics a	nd Maximum Ratings					
	Source to Drain Diode, Forward Volta	ge V _{GS} = 0V, I _S = 12.8A (note 2)		0.84	1.2	V	
V _{SD}							
V _{SD} t _{rr}	Reverse Recovery Time	$I_F = 12.8A, d_{iF}/d_t = 100A/\mu s$		19	29	ns	

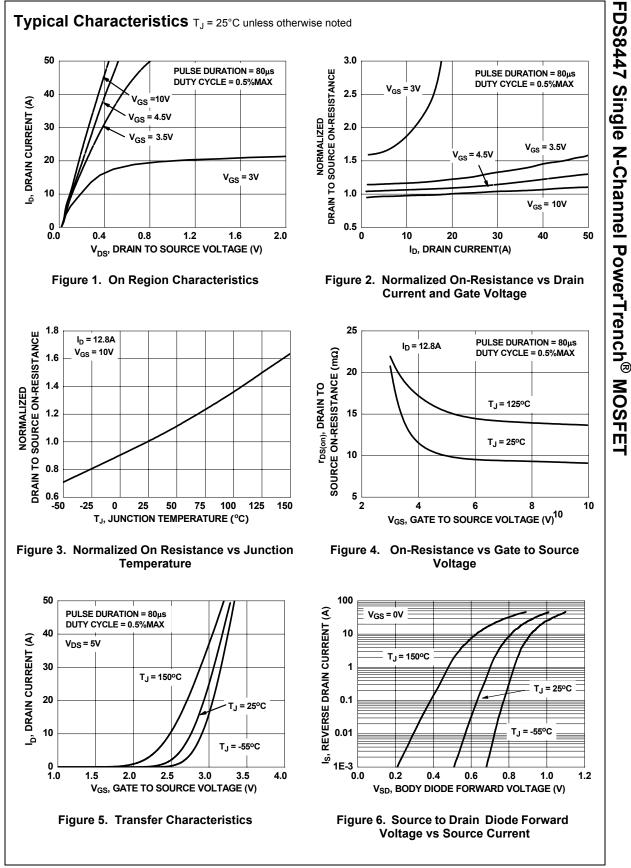
1: R_{0JA} is the sum of the junction-to-case and case-to- ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.



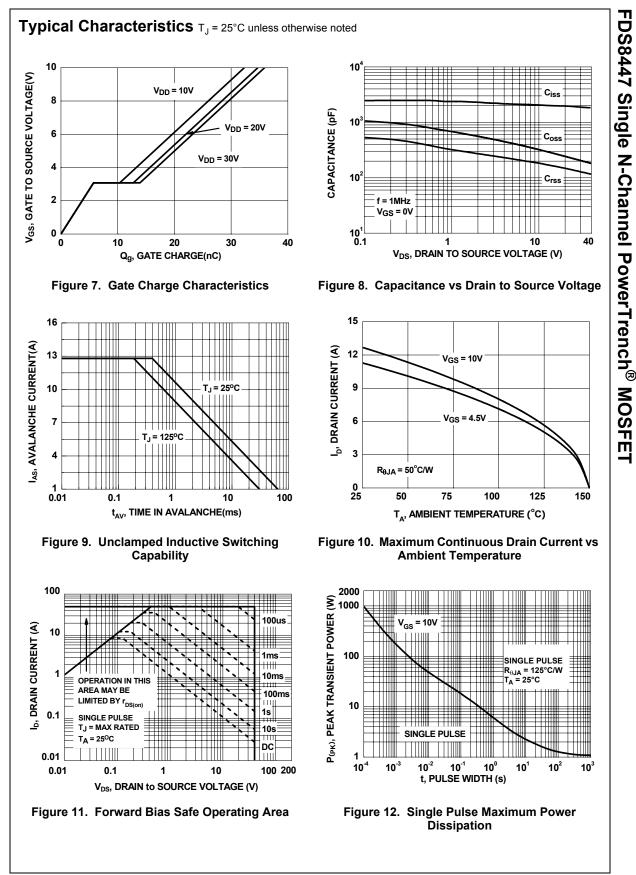
2: Pulse Test: Pulse Width < 300 us, Duty Cycle < 2.0%. **3:** Starting T_J = 25°C, L = 3mH, I_{AS} = 10A, V_{DD} = 40V, V_{GS} = 10V.

a) 50°C/W when mounted on a 1in² pad of 2 oz copper

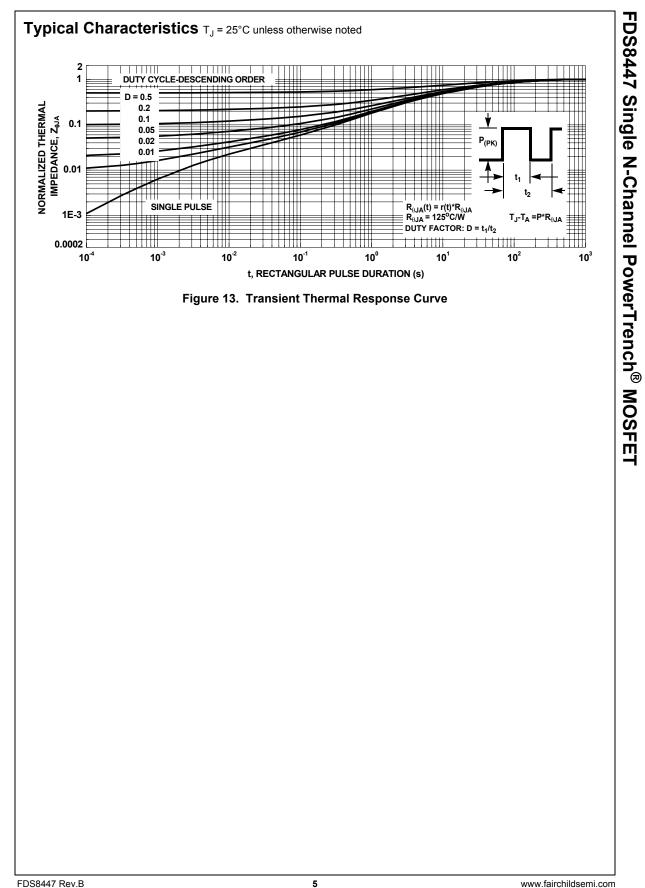
b) 125°C/W when mounted on a minimum pad .



FDS8447 Rev.B



FDS8447 Rev.B





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